

Nove pobude za delo v IEC – APRIL 2026

Referenčna oznaka	Naslov	Tehnični odbor	Odbor (SIST)
110/1846/NP	PNW 110-1846 ED1: <p>3D displays - Part 22-3: Measuring methods for autostereoscopic displays - Ambient properties</p>	TC 110	NI AKTIVNO PODROČJE
113/970/NP	PNW TS 113-970 ED1: Nanomanufacturing - Key control characteristics - Part 13-1: Surface functionalized nanoparticles - Carboxyl groups content: conductometric titration	TC 113	NI AKTIVNO PODROČJE
115/441/NP	PNW TS 115-441 ED1: Specification of Functional Performance of Grid-forming VSC-HVDC systems	TC 115	NI AKTIVNO PODROČJE
32C/683/NP	PNW 32C-683 ED1: Fire-extinguishing thermal-links	SC 32C	SIST/TC EVA
47/3016/NP	PNW 47-3016 ED1: Semiconductor device - The recognition criteria of defects in indium phosphide epitaxial wafers - Part 2: Test method for defects using optical microscopy	TC 47	NI AKTIVNO PODROČJE
47/3017/NP	PNW 47-3017 ED1: Semiconductor device - The recognition criteria of defects in indium phosphide epitaxial wafers - Part 3: Test method for defects using scanning electron microscopy	TC 47	NI AKTIVNO PODROČJE
47D/1008/NP	PNW 47D-1008 ED1: Thermal standardization on semiconductor packages - Part 2-3: 3D thermal simulation models of semiconductor packages for steady-state analysis - LQFP packages	SC 47D	NI AKTIVNO PODROČJE
47E/894/NP	Replaced by 47E/894A/NP	SC 47E	NI AKTIVNO PODROČJE
47E/894A/NP	PNW 47E-894 ED1: Semiconductor devices - Part 14-XX: Semiconductor sensors - Performance test method for capacitive fingerprint sensors	SC 47E	NI AKTIVNO PODROČJE
47E/895/NP	PNW 47E-895 ED1: Semiconductor devices - Part 14-15: Semiconductor sensors - Performance test method of dynamic vision sensors	SC 47F	NI AKTIVNO PODROČJE
47F/555/NP	PNW 47F-555 ED1: Semiconductor devices - Micro-electromechanical devices - Part 65: Test methods for electrical stimulation environment and Electrophysiological measurement using 3D Cell-tissues Models with MEMS chips	TC 51	NI AKTIVNO PODROČJE
51/1618/NP	PNW 51-1618 ED1: Ferrite cores - Guidelines on dimensions and the limits of surface irregularities - Part 17: Balun-cores	SC 62A	NI AKTIVNO PODROČJE
62A/1735/NP	PNW TS 62A-1735 ED1: Medical devices -- Guidance on the application of ISO 14971 -- Part 1: General	SC 8A	NI AKTIVNO PODROČJE
8A/229/NP	PNW TS 8A-229 ED1: Interconnection of converter-based resources with power systems - Part 2: General requirements for marine energy generation	SC 8A	NI AKTIVNO PODROČJE

8A/230/NP	PNW TS 8A-230 ED1: Interconnection of converter-based resources with power systems - Part 10: Framework for the capability and performance of grid forming functions	SC 8B	NI AKTIVNO PODROČJE
8B/285/NP	PNW TS 8B-285 ED1: Microgrid - Part 3-7: Technical requirements - Data center microgrid monitoring, control, and energy management system	ISO/IEC JTC 1/SC 25	NI AKTIVNO PODROČJE
JTC1-SC25/3361/NP	PNW TS JTC1-SC25-3361 ED1: Information technology – Generic cabling systems – Part 100: Classification of optical fibre channels	ISO/IEC JTC 1/SC 43	NI AKTIVNO PODROČJE